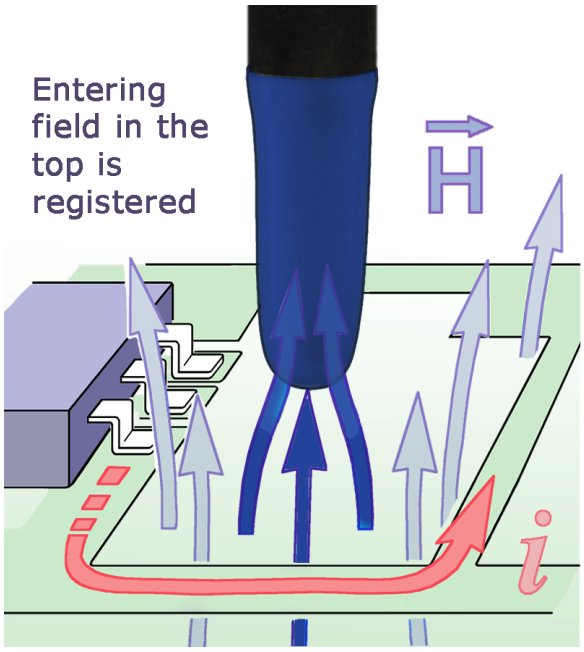
LF-B 3

H-Field Probe 100 kHz up to 50 MHz



Short description

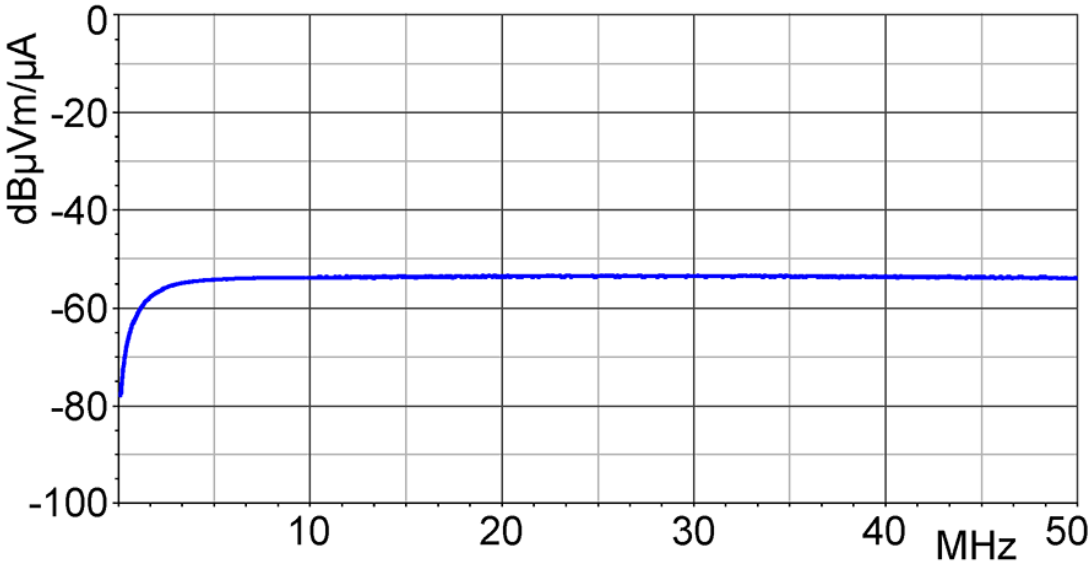
The measuring coil of the H-field probe LF-B 3 sits orthogonally to the shaft. Using the probe tip perpendicularly ensures its correct placement directly on the assembly or device to be measured.
This allows for use at places on the surface of printed circuit boards typically hard to access, e.g. between large components of switching controllers.

The probe LF-B 3 is a passive near-field probe. The measuring coil in the LF-B 3 probe is rotated 90° in contrast to its position in the LF-R 3 probe. The LF-B 3 detects magnetic field lines emitted from the measured object at 90°. Magnetic field lines which enter the probe laterally are not detected. The near-field probe is small and handy. It has a current attenuating sheath and is, therefore, electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The H-field probe does not have an internal terminating resistance of 50 Ω.

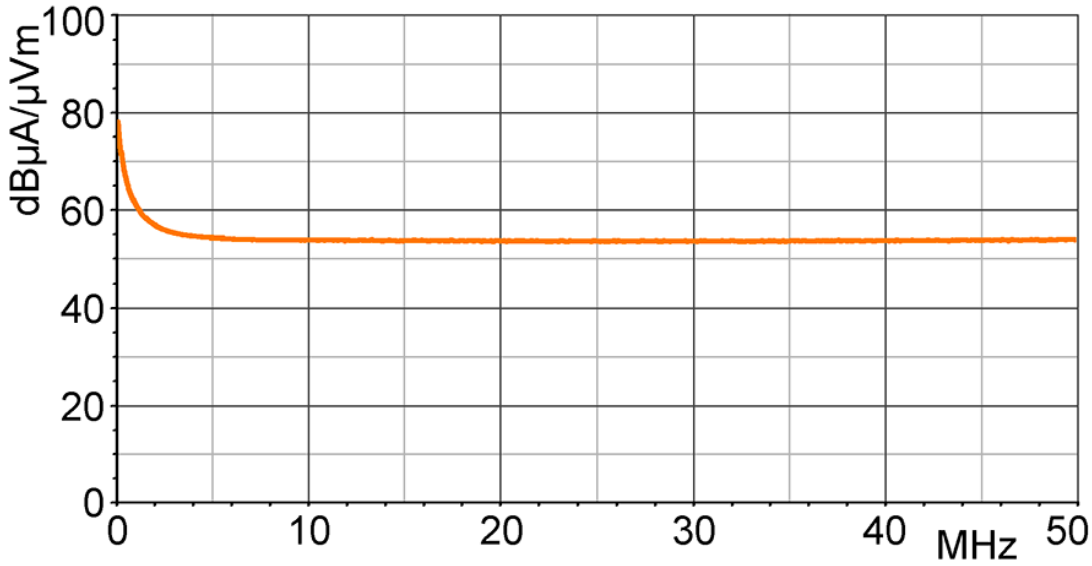
Technical parameters

Frequency range	100 kHz ... 50 MHz
Resolution	≈ 2 mm
Probe head dimensions	Ø ≈ 4 mm
Connector - output	SMB, male, jack
Weight	15 g

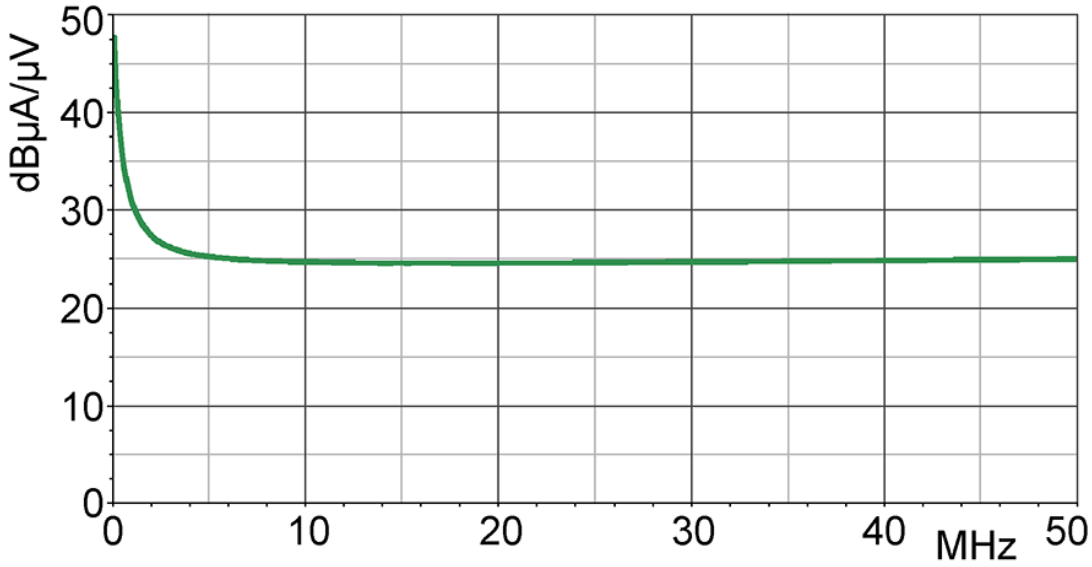
Frequency response [dBµV] / [dBµA/m]



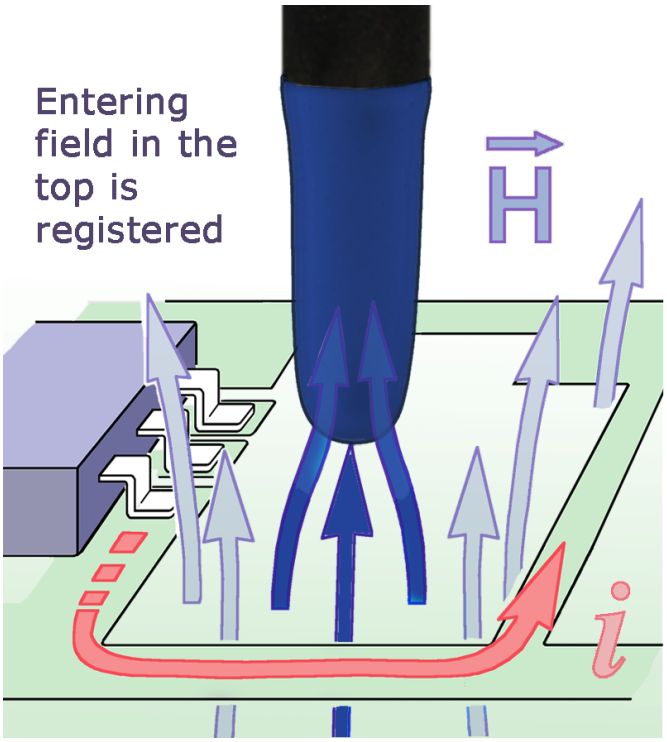
H-field correction curve [dBµA/m] / [dBµV]



Current correction curve [dBµA] / [dBµV]



Measuring principles



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Probe head